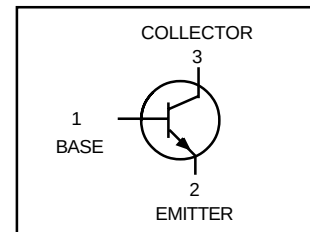
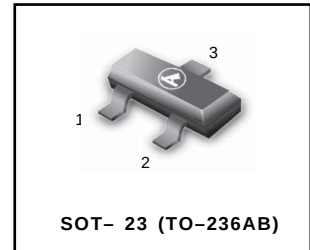


Epitaxial planar type NPN silicon transistor

L2SD2114KVL T1G Series

●Features

- 1) High DC current gain.
 $h_{FE} = 1200$ (Typ.)
- 2) High emitter-base voltage.
 $V_{EBO} = 12V$ (Min.)
- 3) LOW $V_{CE(sat)}$.
 $V_{CE(sat)} = 0.18V$ (Typ.)
($I_C / I_B = 500mA / 20mA$)
- 4) We declare that the material of product compliance with RoHS requirements.



●Absolute maximum ratings (Ta=25°C)

Parameter	Symbol	Limits	Unit
Collector-base voltage	V_{CBO}	25	V
Collector-emitter voltage	V_{CEO}	20	V
Emitter-base voltage	V_{EBO}	12	V
Collector current	I_C	0.5	A(DC)
		1	A(Pulse) *
Collector power dissipation	P_C	0.2	W
Junction temperature	T_j	150	°C
Storage temperature	T_{stg}	-55~+150	°C

* Single pulse $P_w=100ms$

●Electrical characteristics (Ta=25°C)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Conditions
Collector-base breakdown voltage	BV_{CBO}	25	—	—	V	$I_C=10\mu A$
Collector-emitter breakdown voltage	BV_{CEO}	20	—	—	V	$I_C=1mA$
Emitter-base breakdown voltage	BV_{EBO}	12	—	—	V	$I_E=10\mu A$
Collector cutoff current	I_{CBO}	—	—	0.5	μA	$V_{CB}=20V$
Emitter cutoff current	I_{EBO}	—	—	0.5	μA	$V_{EB}=10V$
Collector-emitter saturation voltage	$V_{CE(sat)}$	—	0.18	0.4	V	$I_C/I_B=500mA/20mA$
DC current transfer ratio	h_{FE}	820	—	2700	—	$V_{CE}=3V, I_C=10mA$
Transition frequency	f_T^*	—	350	—	MHz	$V_{CE}=10V, I_E=-50mA, f=100MHz$
Output capacitance	C_{ob}	—	8.0	—	pF	$V_{CB}=10V, I_E=0A, f=1MHz$
Output On-resistance	R_{on}	—	0.8	—	pF	$I_B=1mA, V_i=100mV(rms), f=1kHz$

* Measured using pulse current

● h_{FE} Values Classification, Device Marking and Ordering Information

Device	h_{FE}	Marking	Shipping
L2SD2114KVL T1G	820~1800	BV	3000/Tape&Reel
L2SD2114KVL T3G	820~1800	BV	10000/Tape&Reel
L2SD2114KWLT1G	1200~2700	BW	3000/Tape&Reel
L2SD2114KWLT3G	1200~2700	BW	10000/Tape&Reel

L2SD2114KVLT1G Series

●Electrical characteristic curves

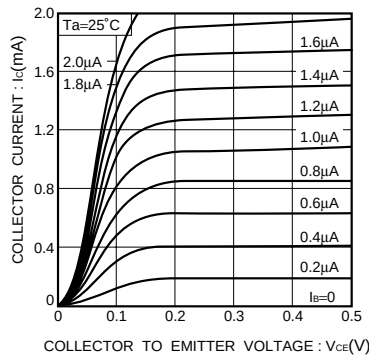


Fig.1 Grounded emitter output characteristics(I)

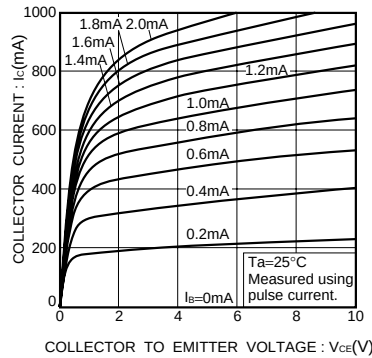


Fig.2 Grounded emitter output characteristics(II)

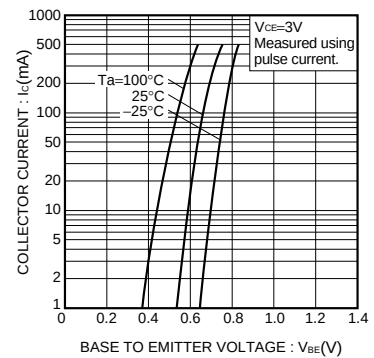


Fig.3 Grounded emitter propagation characteristics

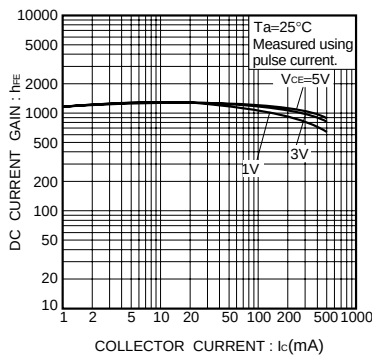


Fig.4 DC current gain vs. collector current(I)

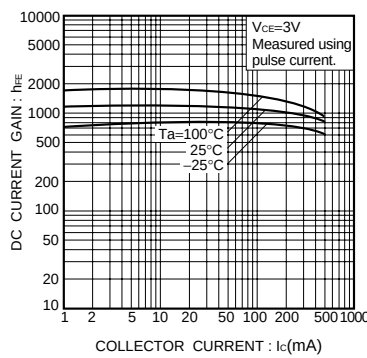


Fig.5 DC current gain vs. collector current(II)

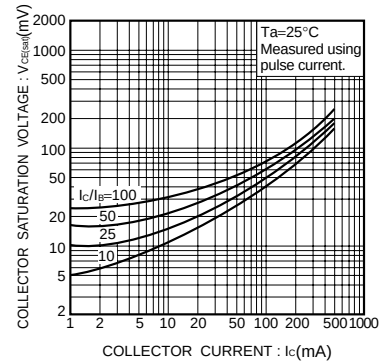


Fig.6 Collector-emitter saturation voltage vs. collector current(I)

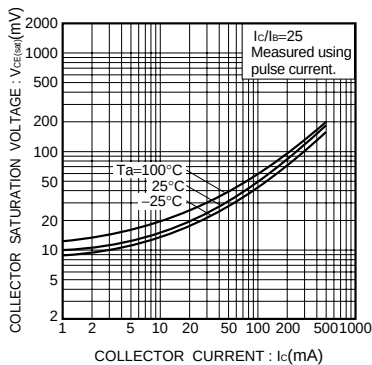


Fig.7 Collector-emitter saturation voltage vs. collector current(II)

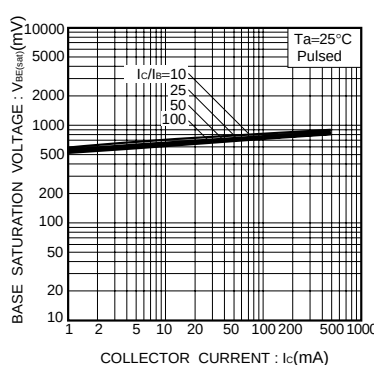


Fig.8 Base-emitter saturation voltage vs. collector current(I)

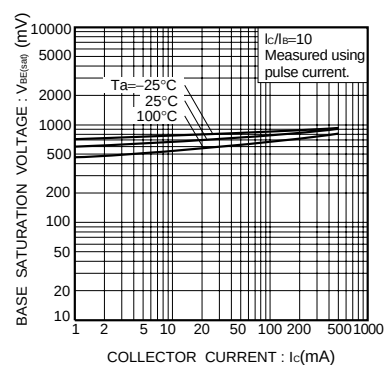


Fig.9 Base-emitter saturation voltage vs. collector current(II)

L2SD2114KVLT1G Series

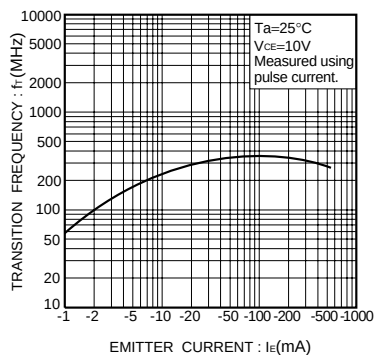


Fig.10 Gain bandwidth product vs. emitter current

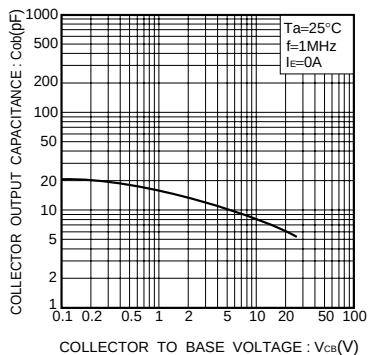


Fig.11 Collector output capacitance vs. collector-base voltage

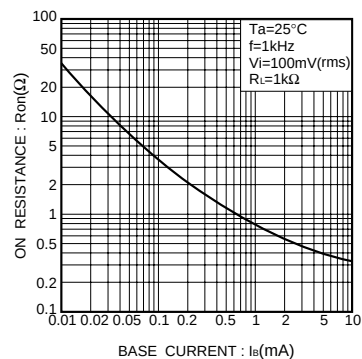
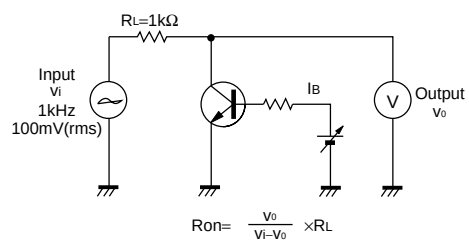


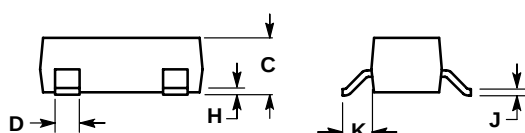
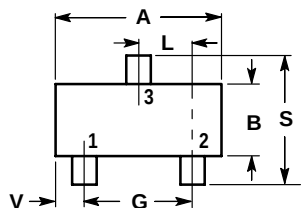
Fig.12 Output-on resistance vs. base current

●Ron measurement circuit



L2SD2114KVLT1G Series

SOT-23



NOTES:

1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: INCH.

DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	0.1102	0.1197	2.80	3.04
B	0.0472	0.0551	1.20	1.40
C	0.0350	0.0440	0.89	1.11
D	0.0150	0.0200	0.37	0.50
G	0.0701	0.0807	1.78	2.04
H	0.0005	0.0040	0.013	0.100
J	0.0034	0.0070	0.085	0.177
K	0.0140	0.0285	0.35	0.69
L	0.0350	0.0401	0.89	1.02
S	0.0830	0.1039	2.10	2.64
V	0.0177	0.0236	0.45	0.60

PIN 1. ANODE
2. NO CONNECTION
3. CATHODE

